MA and LA Package Generic Evaluation Board User Guide

DESCRIPTION

Generic evaluation boards offer a method for quickly evaluating Allegro current sensors in a lab environment without needing a custom circuit board. This document describes the use of the MA/LA current sensor evaluation board. This evaluation board (ACSEVB-MA16-LA16, TED-0004111) is intended for use with any MA or LA package (16-pin SOICW Allegro current sensor).

FEATURES

- Enhanced thermal performance:
 - □ 6-layer PCB with 2 oz copper weight on all layers
 - □ Nonconductive filled Via-In-Pad used
 - ☐ High performance FR4 material with 180°C glass transition temperature
- Flexible instrument connection:
 - ☐ Standard Keystone test points, SMA/SMB connector or 2-pin headers options are provided
- Sensor integrated current loop resistance can be measured directly on the evaluation board; voltage drop can be measured for approximating power loss in the package

EVALUATION BOARD CONTENTS

- Bare printed circuit board without populated components
 - □ NOTE: It is up to the user to assemble the board with the desired current sensor. This board does not come populated with an Allegro current sensor.
- Recommended bill of materials (BOM) for all compatible current sensors are listed in the Bill of Materials section.

Table of Contents

| Description | 1 |
|---------------------------------------|---|
| Features | 1 |
| Evaluation Board Contents | 1 |
| Using the Evaluation Board | 2 |
| Performance Data | 3 |
| Schematic | 4 |
| Layout | 5 |
| Bill of Materials | 6 |
| Related Links and Application Support | 7 |
| Revision History | |

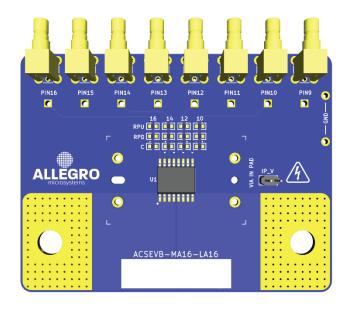


Figure 1: MA/LA Evaluation Board

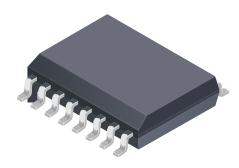


Figure 2: SOIC-W Package (MA/LA Package)

USING THE EVALUATION BOARD

Evaluation Board Components

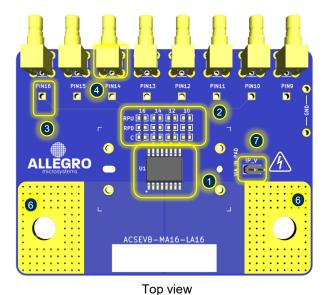
- 1. U1 is an MA/LA package footprint (Pin 1 is on bottom left side, see the small white dot)
- 2. U1 pins allow the option to connect:
 - ☐ RPU: Pull-up resistor to VCC
 - □ RPD: Pull-down resistor to GND
 - ☐ C: decoupling or load capacitor to GND
 - □ All passive components are 0603 package size
- 3. Keystone 5005 test points (e.g., Digikey #36-5005-ND)
- Standard SMB/SMA connector (e.g., Digikey #1868-1429-ND)
- 5. 2-pin 100 mil header connector option (note: either SMB or header can be assembled)
- 6. Primary current cables mounting positions (positive current flow direction is left to right)
- 7. 2-pin 100 mil header connector for voltage drop measurement across the integrated current loop of the current sensor
- 8. RB1, RB2, RB3, and RB4: rubber bumper mounting positions (e.g., Digikey #SJ61A6-ND)

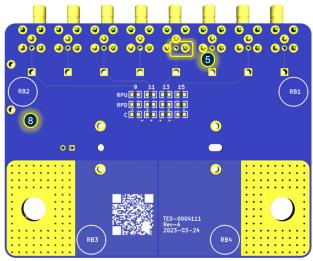
Evaluation Board Procedure

CONNECTING TO THE EVALUATION BOARD

The best way to connect measurement instruments to the evaluation board is to use SMB/SMA or 2-pin headers connectors along with coaxial cables. This configuration will be most resilient to external coupling, and it is preferred way for measurement, e.g., high speed dI/dt transients.

Keystone test point are a convenient way to connect any instrument, but is it recommended for DC setups only.





Bottom view

Figure 3: MA/LA Current Sensor Evaluation Board Reference Image



EVALUATION BOARD PERFORMANCE DATA

Thermal Rise vs. Primary Current

Self-heating due to the flow of current in the package IP conductor should be considered during the design of any current sensing system. The sensor, printed circuit board (PCB), and contacts to the PCB will generate heat and act as a heat sink as current moves through the system.

The thermal response is highly dependent on PCB layout, copper thickness, cooling techniques, and the profile of the injected current. The current profile includes peak current value, current on-time, and duty cycle.

Placing vias under the copper pads of the Allegro current sensor evaluation board minimize the current path resistance and improves heatsinking to the PCB, while vias outside of the pads limit the current path to the top of the PCB trace and have worse heatsinking under the part (see Figure 4 and Figure 5 below). The ACSEVB-MA16-LA16 does include vias in pad and is recommended to improve thermal performance.

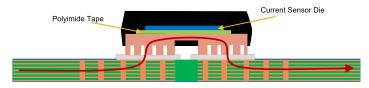


Figure 4: Vias Under Copper Pads (not to scale)

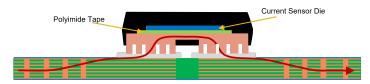


Figure 5: No Vias Under Copper Pads (not to scale)

The plot in Figure 6 shows the measured rise in steady-state die temperature of the MA package versus DC continuous current at an ambient temperature, T_A, of 25 °C for two board designs: filled vias under copper pads and no vias under copper pads.

The plot in Figure 7 shows the measured rise in steady-state die temperature of the LA package versus DC continuous current at an ambient temperature, T_A , of 25 °C for two board designs: filled vias under copper pads and no vias under copper pads.

Note: Using in-pad vias has better thermal performance that no in-pad vias, and this is the design the ACSEVB-MA16-LA16 uses.

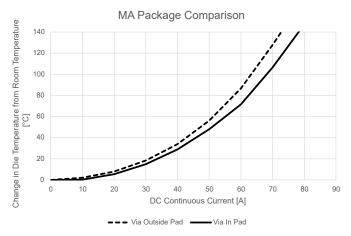


Figure 6: MA Package Comparison with and without In-Pad Vias

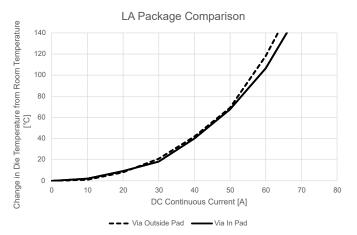


Figure 7: LA Package Comparison with and without In-Pad Vias

The thermal capacity of the MA and LA package should be verified by the end user in the application's specific conditions. The maximum junction temperature, $T_{J(max)}$ (165°C), should not be exceeded. Measuring the temperature of the top of the package is a close approximation of the die temperature.



SCHEMATIC

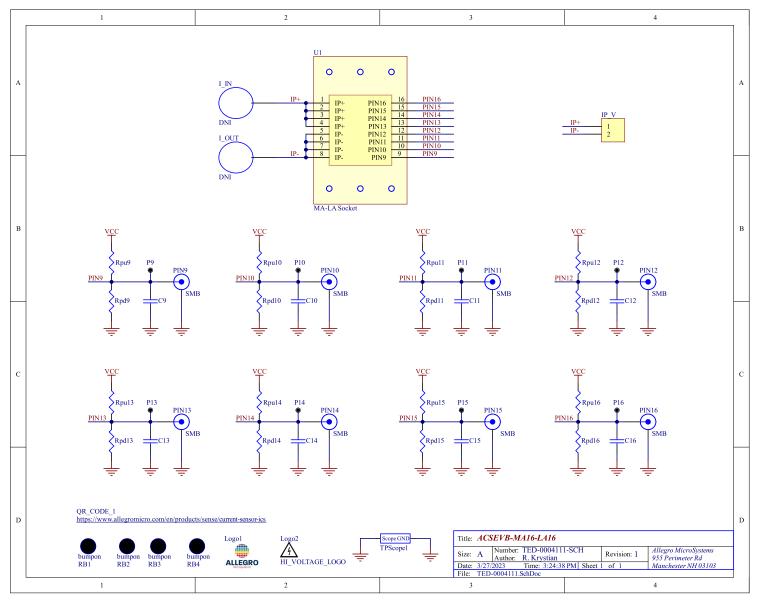


Figure 8: MA/LA Generic Evaluation Board Schematic

LAYOUT

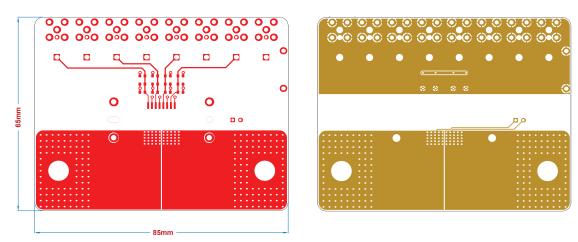


Figure 9: MA/LA Generic Evaluation Board Top Layer (left) and Interior Layer 1

The MA/LA Current Sensor Evaluation board features test points that allow the current sensor integrated current loop resistance to be measured directly from the evaluation board. The voltage drop sensing is routed in the first internal layer (as to not reduce isolation spec of the package). As a consequence, the voltage drop will include the parasitic resistance of the vias between the top layer and the first interior layer.

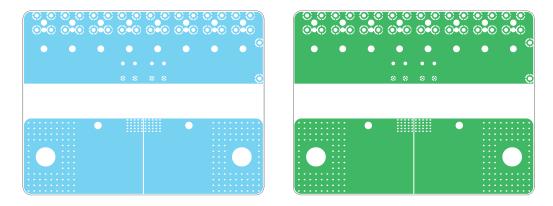


Figure 10: MA/LA Generic Evaluation Board Interior Layer 2 (left) and Interior Layer 3

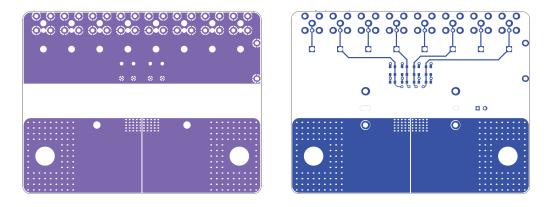


Figure 11: MA/LA Generic Evaluation Board Interior Layer 4 (left) and Bottom Layer



BILL OF MATERIALS

Components listed are based on the typical application circuit given in the respective device datasheet.

Table 1: Evaluation Board Bill of Materials

ACS37002 ASSEMBLY VARIANT (MA AND LA)

| Pin | Terminal | Components | |
|------------|------------|---|--|
| 1, 2, 3, 4 | IP+ | Towningle for assemble being accorded for a distance like | |
| 5, 6, 7, 8 | IP- | Terminals for current being sensed; fused internally | |
| 9 | OCF | Overcurrent fault, open-drain, requires pull-up resistor | |
| 10 | VCC | Device power supply terminal, connected to supply voltage | |
| 11 | VOC | Overcurrent fault operation point input, connected to resistor divider or external power source | |
| 12 | VOUT | Analog output representing the current flowing through IP, optional load capacitance or load resistance | |
| 13 | VREF | Zero current voltage reference | |
| 14 | GAIN_SEL_1 | Gain selection bit 1, connected to high or GND | |
| 15 | GND | Device ground terminal, connected to GND | |
| 16 | GAIN_SEL_0 | Gain selection bit 0, connected to high or GND | |

Table 2: Evaluation Board Bill of Materials

ACS724/25 ASSEMBLY VARIANT (MA)

| Pin | Terminal | Components |
|---------------|------------|---|
| 1, 2, 3, 4 | IP+ | Terminals for current being sensed; fused internally |
| 5, 6, 7, 8 | IP- | |
| 9, 11, 14, 16 | NC | No internal connection; recommended to be left unconnected in order to maintain high creepage |
| 10 | VCC | Device power supply terminal, connected to supply voltage |
| 12 | VOUT | Analog output representing the current flowing through IP, optional load capacitance or load resistance |
| 13 | FILTER | Terminal for external capacitor that sets bandwidth |
| 14 | GAIN_SEL_1 | Gain selection bit 1, connected to high or GND |
| 15 | GND | Device ground terminal, connected to GND |

Table 3: Evaluation Board Bill of Materials

ACS732/733 ASSEMBLY VARIANT (MA AND LA)

| Pin | Terminal | Components | |
|------------|----------|---|--|
| 1, 2, 3, 4 | IP+ | Towain ale for compath air a paragraph for and intermally | |
| 5, 6, 7, 8 | IP- | Terminals for current being sensed; fused internally | |
| 9, 10 | GND | Device ground terminal, connected to GND | |
| 11 | PROGRAM | Programming input pin for factory calibration. Connect to GND for best ESD performance | |
| 12 | VOUT | Analog output representing the current flowing through IP, optional load capacitance or load resistance | |
| 13 | FAULT | Overcurrent fault, open-drain, requires pull-up resistor | |
| 14 | VOC | Overcurrent fault operation point input, connected to resistor divider or external power source | |
| 15, 16 | VCC | Device power supply terminal, connected to supply voltage | |



RELATED LINKS AND APPLICATION SUPPORT

Table 4: Related Documentation and Application Support

| Documentation | Summary | Location |
|---|---|---|
| Allegro Current Sensors Webpage | Product datasheet defining common electrical characteristics and performance characteristics | https://www.allegromicro.com/en/products/ sense/current-sensor-ics |
| Allegro Current Sensor Package Documentation | Schematic files, step files, package images | https://www.allegromicro.com/en/design- support/packaging |
| An Effective Method for Characterizing System Bandwidth in Complex Current Sensor Applications | Application note describing methods used by Allegro to measure and quantify system bandwidth | https://allegromicro.com/en/insights-and-innovations/technical-documents/hall-effect-sensor-ic-publications/an-effective-method-for-characterizing-system-bandwidth-an296169 |
| DC and Transient Current Capability/Fuse Characteristics of Surface Mount Current Sensor ICs | DC and Transient Current Capability/Fuse Characteristics of Surface Mount Current Sensor ICs | https://www.allegromicro.com/en/Insights-and-Innovations/Technical-Documents/Hall-Effect-Sensor-IC-Publications/DC-and-Transient-Current-Capability-Fuse-Characteristics.aspx |
| High-Current Measurement with Allegro Current Sensor IC and Ferromagnetic Core: Impact of Eddy Currents | Application note focusing on the effects of alternating current on current measurement | https://allegromicro.com/en/insights-and-innovations/technical-documents/hall-effect-sensor-ic-publications/an296162_a1367_current-sensor-eddy-current-core |
| Secrets of Measuring Currents Above 50 Amps | Application note regarding current measurement greater than 50 A | https://allegromicro.com/en/insights-and-innovations/technical-documents/hall-effect-sensor-ic-publications/an296141-secrets-of-measuring-currents-above-50-amps |
| Allegro Hall-Effect Sensor ICs | Application note describing Hall-effect principles | https://allegromicro.com/en/insights-and-innovations/technical-documents/hall-effect-sensor-ic-publications/allegro-hall-effect-sensor-ics |
| Hall-Effect Current Sensing in Electric and Hybrid Vehicles | Application note providing a greater understanding of hybrid electric vehicles and the contribution of Hall-effect sensing technology | https://allegromicro.com/en/insights-and-innovations/technical-documents/hall-effect-sensor-ic-publications/hall-effect-current-sensing-in-electric-and-hybrid-vehicles |
| Hall-Effect Current Sensing in Hybrid Electric Vehicle (HEV) Applications | Application note providing a greater understanding of hybrid electric vehicles and the contribution of Hall-effect sensing technology | https://allegromicro.com/en/insights- and-innovations/technical-documents/ hall-effect-sensor-ic-publications/hall-effect- current-sensing-in-hybrid-electric-vehicle-hev- applications |
| Achieving Closed-Loop Accuracy in Open-Loop Current Sensors | Application note regarding current sensor IC solutions that achieve near closed-loop accuracy using open-loop topology | https://allegromicro.com/en/insights-and-innovations/technical-documents/hall-effect-sensor-ic-publications/achieving-closed-loop-accuracy-in-open-loop-current-sensors |
| Allegro Current Sensor ICs Can Take the Heat! Unique Packaging Options for Every Thermal Budget | Application note regarding current sensors and package selection based on thermal capabilities | https://www.allegromicro.com/-/media/files/ application-notes/an296190-current-sensor- thermals.pdf |
| Explanation Of Error Specifications For Allegro Linear Hall-Effect-Based Current Sensor Ics And Techniques For Calculating Total System Error | Application note describing error sources and their effect on the current sensor output | https://www.allegromicro.com/-/media/files/ application-notes/an296181-acs72981-error- calculation.pdf |



Revision History

| Number | Date | Description | |
|--------|-----------------|-----------------|--|
| _ | August 17, 2023 | Initial release | |

Copyright 2023, Allegro MicroSystems.

Allegro MicroSystems reserves the right to make, from time to time, such departures from the detail specifications as may be required to permit improvements in the performance, reliability, or manufacturability of its products. Before placing an order, the user is cautioned to verify that the information being relied upon is current.

Allegro's products are not to be used in any devices or systems, including but not limited to life support devices or systems, in which a failure of Allegro's product can reasonably be expected to cause bodily harm.

The information included herein is believed to be accurate and reliable. However, Allegro MicroSystems assumes no responsibility for its use; nor for any infringement of patents or other rights of third parties which may result from its use.

Copies of this document are considered uncontrolled documents.



Mouser Electronics

Authorized Distributor

Click to View Pricing, Inventory, Delivery & Lifecycle Information:

Allegro MicroSystems:

ACSEVB-MA16-LA16